

# T513X107K020BH6320

T513 HRA, Tantalum, MnO<sub>2</sub> Tantalum, HRA Multi-Anode, 100 uF, 10%, 20 VDC, SMD, MnO<sub>2</sub>, Molded, Military Equivalent, MAT High Reliability, B (0.1%/1000 Hrs), 40 mOhms, 4.3 mm, 2817 / 7343



Click [here](#) for the 3D model.

## General Information

Series	T513 HRA
Dielectric	MnO <sub>2</sub> Tantalum
Style	SMD Chip
Description	SMD, MnO <sub>2</sub> , Molded, Military Equivalent, MAT High Reliability
Features	Low ESR
RoHS	No
Prop 65	<b>WARNING:</b> Cancer and reproductive harm - <a href="https://www.p65warnings.ca.gov/">https://www.p65warnings.ca.gov/</a>
SCIP Number	b064b03e-bd75-42af-b342-1fe94dec2340
Termination	Tin Lead (SnPb)
Typical Component Weight	430.15 mg

## Dimensions

L	7.3mm +/-0.3mm
W	4.3mm +/-0.3mm
H	4mm +/-0.3mm
T	0.13mm REF
S	1.3mm +/-0.3mm
F	2.4mm +/-0.1mm
A	3.8mm MIN
B	0.5mm +/-0.15mm
E	3.5mm REF
G	3.5mm REF
P	1.7mm REF
R	1mm REF
X	0.1mm +/-0.1mm REF

## Specifications

Capacitance	100 uF
Tolerance	10%
Voltage DC	20 VDC (85C), 13.4 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	8% 120Hz 25C
Failure Rate	B (0.1%/1000 Hrs)
ESR	40 mOhms (100kHz 25C)
Ripple Current	2030 mA (rms, 100kHz 25C)
Leakage Current	20 uA (5min 25°C)
Testing and Reliability	10 Cycles Surge Current Testing At -55C +/-5C And +85C +/-5C After Weibull

## Packaging Specifications

Packaging	T&R, 178mm
Packaging Quantity	500

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